

MOSFETs Silicon P-/N-Channel MOS

# SSM6L826R

### 1. Applications

- · Power Management Switches
- · Motor Drivers

#### 2. Features

(1) Low drain-source on-resistance

Q1 N-channel:

 $R_{\mathrm{DS(ON)}}$  = 46 m $\Omega$  (max) (@V\_{\mathrm{GS}} = 10 V)

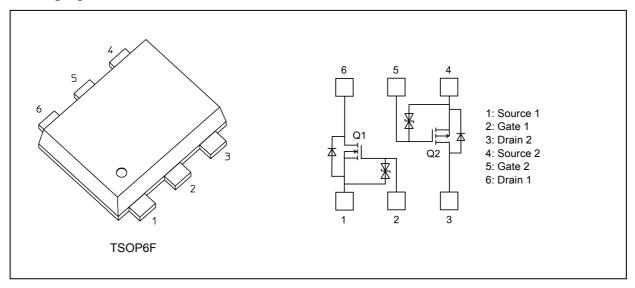
 $R_{\mathrm{DS(ON)}} = 64 \ \mathrm{m}\Omega \ (\mathrm{max}) \ (@V_{\mathrm{GS}} = 4.5 \ \mathrm{V})$ 

Q2 P-channel:

 $R_{\mathrm{DS(ON)}} = 45~\mathrm{m}\Omega~(\mathrm{max})~(@V_{\mathrm{GS}} = -10~\mathrm{V})$ 

 $R_{DS(ON)} = 73 \text{ m}\Omega \text{ (max) } (@V_{GS} = -4.5 \text{ V})$ 

## 3. Packaging and Internal Circuit





#### 4. Absolute Maximum Ratings (Note)

## 4.1. Q1 Absolute Maximum Ratings (Unless otherwise specified, Ta = 25 °C)

Characteristics			Symbol	Rating	Unit
Drain-source voltage			$V_{DSS}$	30	V
Gate-source voltage			V <sub>GSS</sub>	+20/-12	
Drain current (DC)		(Note 1)	I <sub>D</sub>	4	Α
Drain current (pulsed)	(t ≤ 10 ms)	(Note 1), (Note 2)	I <sub>DP</sub>	12	

Note 1: Ensure that the channel temperature does not exceed 150 °C.

Note 2: Pulse width (PW)  $\leq$  10 ms, duty  $\leq$  1 %

#### 4.2. Q2 Absolute Maximum Ratings (Unless otherwise specified, Ta = 25 °C)

Characteristi	cs		Symbol	Rating	Unit
Drain-source voltage			$V_{DSS}$	-30	V
Gate-source voltage			$V_{GSS}$	-20/+10	
Drain current (DC)		(Note 1)	I <sub>D</sub>	-4	Α
Drain current (pulsed)	(t ≤ 10 ms)	(Note 1), (Note 2)	I <sub>DP</sub>	-12	

Note 1: Ensure that the channel temperature does not exceed 150 °C.

Note 2: Pulse width (PW)  $\leq$  10 ms, duty  $\leq$  1 %

# 4.3. Absolute Maximum Ratings (Unless otherwise specified, T<sub>a</sub> = 25 °C) (Q1, Q2 Common)

Cha	racteristics		Symbol	Rating	Unit
Power dissipation		(Note 1)	$P_{D}$	1.0	W
Power dissipation	(t ≤ 10 s)	(Note 1)		1.8	
Channel temperature			T <sub>ch</sub>	150	°C
Storage temperature			T <sub>stg</sub>	-55 to 150	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Device mounted on an FR4 board.(total rating)

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ mm}, \text{ Cu pad: } 645 \text{ mm}^2)$ 

Note: The MOSFETs in this device are sensitive to electrostatic discharge. When handling this device, the worktables, operators, soldering irons and other objects should be protected against anti-static discharge.

Note: The channel-to-ambient thermal resistance, R<sub>th(ch-a)</sub>, and the drain power dissipation, P<sub>D</sub>, vary according to the board material, board area, board thickness and pad area. When using this device, be sure to take heat dissipation fully into account.



#### 5. Electrical Characteristics

## 5.1. Q1 Static Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20/-12 V	_	_	±10	μА
Drain cut-off current	,	I <sub>DSS</sub>	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V	_	_	1	
Drain-source breakdown voltage		V <sub>(BR)DSS</sub>	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	30	_	_	٧
Drain-source breakdown voltage	(Note 1)	V <sub>(BR)DSX</sub>	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = -12 V	18	_	_	
Gate threshold voltage	(Note 2)	$V_{th}$	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 0.1 mA	1.3	_	2.5	
Drain-source on-resistance	(Note 3)	R <sub>DS(ON)</sub>	I <sub>D</sub> = 4.0 A, V <sub>GS</sub> = 10 V	_	33	46	mΩ
			I <sub>D</sub> = 2.0 A, V <sub>GS</sub> = 4.5 V	_	48	64	

Note 1: If a reverse bias is applied between gate and source, this device enters V<sub>(BR)DSX</sub> mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let  $V_{th}$  be the voltage applied between gate and source that causes the drain current ( $I_D$ ) to below (0.1 mA for this device). Then, for normal switching operation,  $V_{GS(ON)}$  must be higher than  $V_{th}$ , and  $V_{GS(OFF)}$  must be lower than  $V_{th}$ . This relationship can be expressed as:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ .

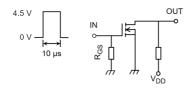
Take this into consideration when using the device.

Note 3: Pulse measurement.

#### 5.2. Q1 Dynamic Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 15 V , V <sub>GS</sub> = 0 V,	_	280	_	pF
Reverse transfer capacitance	C <sub>rss</sub>	f = 1 MHz	_	20		
Output capacitance	C <sub>oss</sub>		_	53		
Switching time (turn-on time)	t <sub>on</sub>	$V_{DD}$ = 15 V, $I_{D}$ = 0.5 A, $V_{GS}$ = 0 to 4.5 V, $R_{GS}$ = 50 $\Omega$	_	18.5		ns
Switching time (turn-off time)	t <sub>off</sub>	Duty ≤ 1%, V <sub>IN</sub> : tr, tf < 5 ns Common source, see Chapter 5.3	_	16.5	_	

#### 5.3. Q1 Switching Time Test Circuit



**Switching Time Test Circuit** 

Input Waveform/Output Waveform

## 5.4. Q1 Gate Charge Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)	$Q_g$	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 4.0 A,	_	2.5	_	nC
Gate-source charge 1	Q <sub>gs1</sub>	V <sub>GS</sub> = 4.5 V	_	1.6	_	
Gate-drain charge	Q <sub>gd</sub>		_	0.5	_	

### 5.5. Q1 Source-Drain Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage	(Note 1)	$V_{DSF}$	I <sub>DR</sub> = 4 A, V <sub>GS</sub> = 0 V	_	0.85	1.2	V

Note 1: Pulse measurement.



## 5.6. Q2 Static Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = -20/+10 V	_	_	±1	μА
Drain cut-off current		I <sub>DSS</sub>	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	-1	
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = -0.25 \text{ mA}, V_{GS} = 0 \text{ V}$	-30	_	_	V
Drain-source breakdown voltage	(Note 1)	$V_{(BR)DSX}$	I <sub>D</sub> = -0.25 mA, V <sub>GS</sub> = 10 V	-20	_	_	
Gate threshold voltage	(Note 2)	$V_{th}$	$V_{DS}$ = -10 V, $I_{D}$ = -0.25 mA	-0.9	_	-2.0	
Drain-source on-resistance	(Note 3)	R <sub>DS(ON)</sub>	$I_D = -4.0 \text{ A}, V_{GS} = -10 \text{ V}$	_	35	45	mΩ
			$I_D = -4.0 \text{ A}, V_{GS} = -4.5 \text{ V}$	_	55	73	mΩ

Note 1: If a reverse bias is applied between gate and source, this device enters  $V_{(BR)DSX}$  mode. Note that the drain-source breakdown voltage is lowered in this mode.

Note 2: Let  $V_{th}$  be the voltage applied between gate and source that causes the drain current ( $I_D$ ) to below (-0.25 mA for this device). Then, for normal switching operation,  $V_{GS(ON)}$  must be higher than  $V_{th}$ , and  $V_{GS(OFF)}$  must be lower than  $V_{th}$ . This relationship can be expressed as:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ .

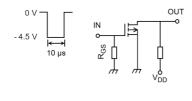
Take this into consideration when using the device.

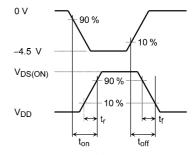
Note 3: Pulse measurement.

# 5.7. Q2 Dynamic Characteristics (Unless otherwise specified, Ta = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C <sub>iss</sub>	$V_{DS} = -15 \text{ V}$ , $V_{GS} = 0 \text{ V}$ ,	_	492	_	pF
Reverse transfer capacitance	C <sub>rss</sub>	f = 1 MHz	_	75	_	
Output capacitance	C <sub>oss</sub>		_	97	_	
Switching time (turn-on time)	t <sub>on</sub>	$V_{DD}$ = -15 V, $I_{D}$ = -2.0 A, $V_{GS}$ = 0 to -4.5 V, $R_{GS}$ = 50 $\Omega$		50		ns
Switching time (turn-off time)	t <sub>off</sub>	Duty $\leq$ 1 %, V <sub>IN</sub> : $t_r$ , $t_f$ $\leq$ 5 ns, Common source, see Chapter 5.8		106.5		

#### 5.8. Q2 Switching Time Test Circuit





**Switching Time Test Circuit** 

Input Waveform/Output Waveform

### 5.9. Q2 Gate Charge Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)		$V_{DD} = -15 \text{ V}, I_{D} = -4.0 \text{ A},$	_	6.2	_	nC
Gate-source charge 1	Q <sub>gs1</sub>	V <sub>GS</sub> = -4.5 V	_	1.5	_	
Gate-drain charge	Q <sub>gd</sub>		_	2.8	_	

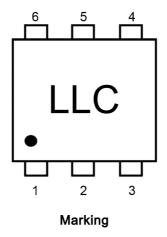
### 5.10. Q2 Source-Drain Characteristics (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage	(Note 1)	$V_{DSF}$	I <sub>DR</sub> = 4 A, V <sub>GS</sub> = 0 V	_	0.85	1.1	V

Note 1: Pulse measurement.



# 6. Marking





#### 7. Characteristics Curves (Note)

### 7.1. Q1 Characteristics Curves

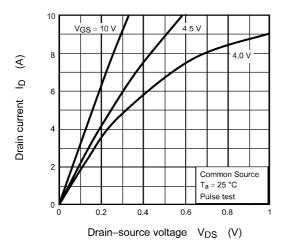


Fig. 7.1.1 I<sub>D</sub> - V<sub>DS</sub>

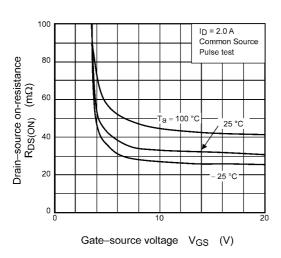


Fig. 7.1.3 R<sub>DS(ON)</sub> - V<sub>GS</sub>

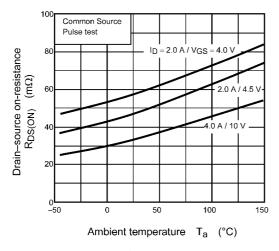


Fig. 7.1.5 R<sub>DS(ON)</sub> - T<sub>a</sub>

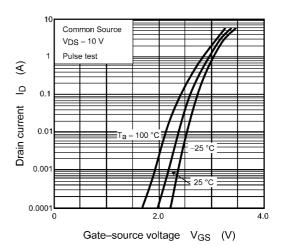


Fig. 7.1.2 I<sub>D</sub> - V<sub>GS</sub>

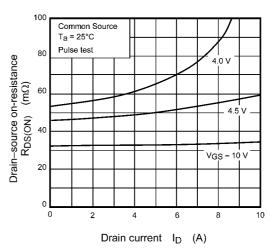


Fig. 7.1.4 R<sub>DS(ON)</sub> - I<sub>D</sub>

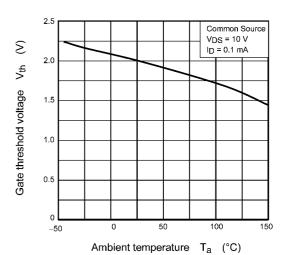


Fig. 7.1.6 V<sub>th</sub> - T<sub>a</sub>



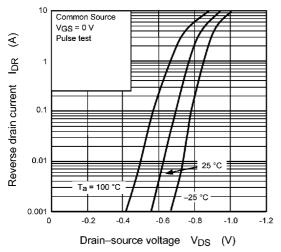


Fig. 7.1.7 IDR - VDS

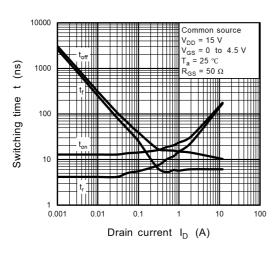


Fig. 7.1.9 t - I<sub>D</sub>

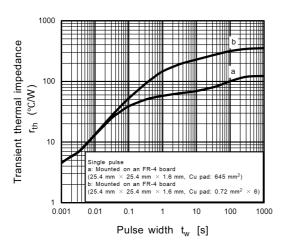


Fig. 7.1.11 rth - tw

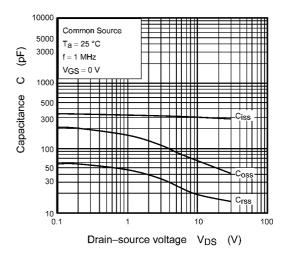


Fig. 7.1.8 C - V<sub>DS</sub>

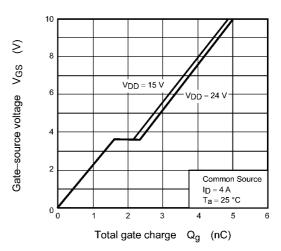


Fig. 7.1.10 Dynamic Input Characteristics

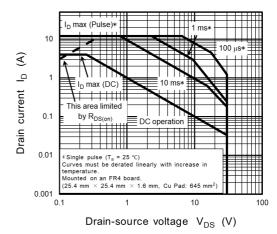


Fig. 7.1.12 Safe Operating Area



#### 7.2. Q2 Characteristics Curves

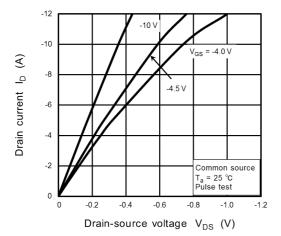


Fig. 7.2.1 I<sub>D</sub> - V<sub>DS</sub>

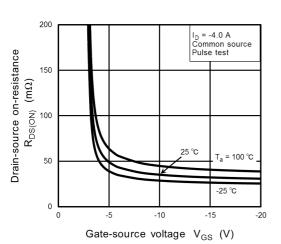


Fig. 7.2.3 R<sub>DS(ON)</sub> - V<sub>GS</sub>

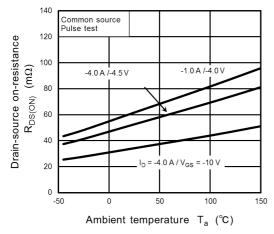


Fig. 7.2.5 R<sub>DS(ON)</sub> - T<sub>a</sub>

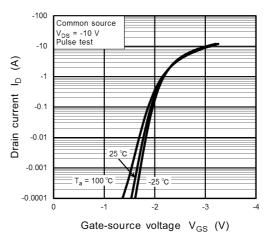


Fig. 7.2.2 I<sub>D</sub> - V<sub>GS</sub>

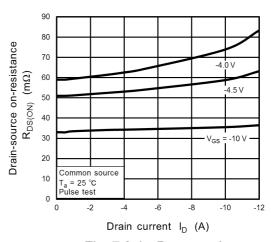


Fig. 7.2.4 R<sub>DS(ON)</sub> - I<sub>D</sub>

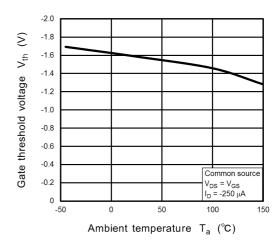


Fig. 7.2.6 V<sub>th</sub> - T<sub>a</sub>



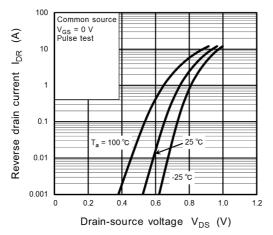


Fig. 7.2.7 IDR - VDS

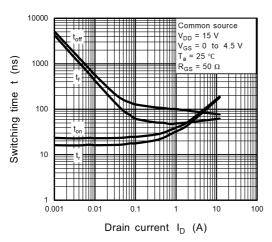


Fig. 7.2.9 t - I<sub>D</sub>

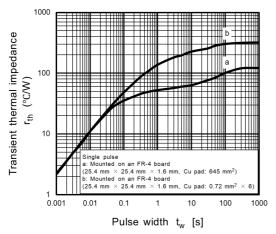


Fig. 7.2.11 r<sub>th</sub> - t<sub>w</sub>

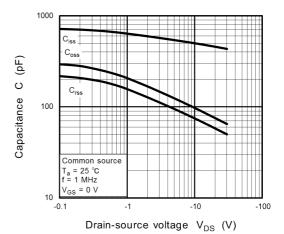


Fig. 7.2.8 C - V<sub>DS</sub>

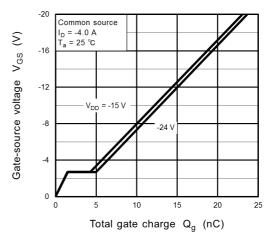


Fig. 7.2.10 Dynamic Input Characteristics

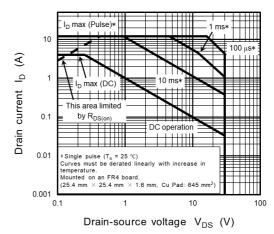


Fig. 7.2.12 Safe Operating Area

Rev.1.0



# 7.3. Characteristics Curves (Q1, Q2 Common)

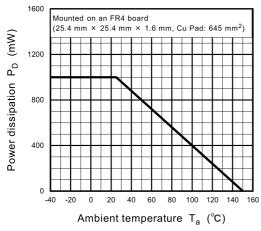


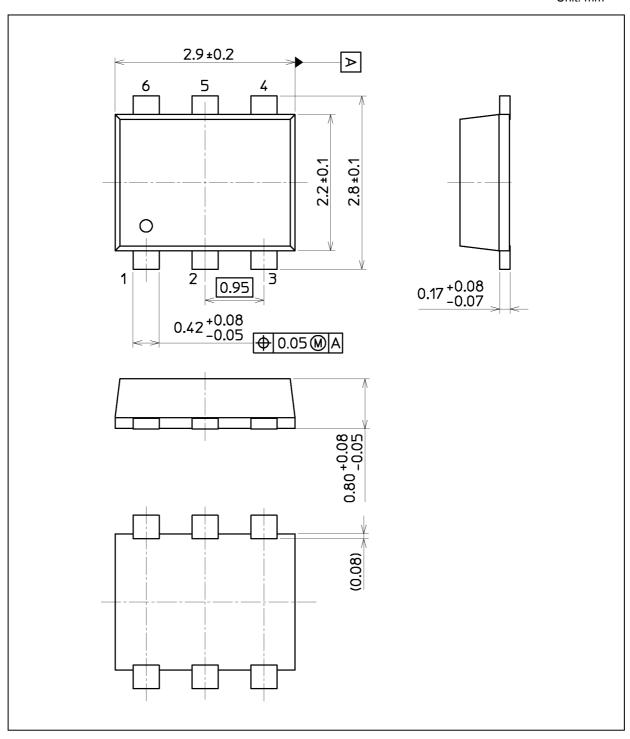
Fig. 7.3.1 P<sub>D</sub> - T<sub>a</sub>

Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



# **Package Dimensions**

Unit: mm



Weight: 0.016 g (typ.)

	Package Name(s)
Nickname: TSOP6F	



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